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APPLICATION NO.	FILING DATE	FIRST NAMED INVENTOR	ATTORNEY DOCKET NO.	CONFIRMATION NO.		
09/844,347	04/27/2001	Jun Zeng	SE1645PD (50042)	2463		
75	590 09/05/2002					
	ER F. REGAN, ESQU	EXAMINER				
ALLEN, DYER P.O. Box 3791	R, DOPPELT, MILBRAT	SOWARD, IDA M				
Orlando, FL 32802-3791			ART UNIT PAPER NUMBER			
		2822				
			DATE MAILED: 09/05/2002			

Please find below and/or attached an Office communication concerning this application or proceeding.

••		Application No.		Applicant(s)	$\frac{1}{n}$				
		09/844,347	7	ZENG, JUN					
Office Action Summary		Examiner		Art Unit	•				
		Ida M Soward		2822					
	The MAILING DATE of this communication app		r sheet with the c		ess				
Period for Reply									
A SHORTENED STATUTORY PERIOD FOR REPLY IS SET TO EXPIRE 3 MONTH(S) FROM THE MAILING DATE OF THIS COMMUNICATION.  - Extensions of time may be available under the provisions of 37 CFR 1.136(a). In no event, however, may a reply be timely filed after SIX (6) MONTHS from the mailing date of this communication.  - If the period for reply specified above is less than thirty (30) days, a reply within the statutory minimum of thirty (30) days will be considered timely.  - If NO period for reply is specified above, the maximum statutory period will apply and will expire SIX (6) MONTHS from the mailing date of this communication.  - Failure to reply within the set or extended period for reply will, by statute, cause the application to become ABANDONED (35 U.S.C. § 133).  - Any reply received by the Office later than three months after the mailing date of this communication, even if timely filed, may reduce any earned patent term adjustment. See 37 CFR 1.704(b).  Status									
1)⊠	Responsive to communication(s) filed on 26.	June 2002 .							
2a)⊠	This action is <b>FINAL</b> . 2b) Th	his action is non-f	inal.						
3) Since this application is in condition for allowance except for formal matters, prosecution as to the merits is closed in accordance with the practice under <i>Ex parte Quayle</i> , 1935 C.D. 11, 453 O.G. 213.  Disposition of Claims									
4)🖂	Claim(s) 23-39 is/are pending in the application	on.							
	4a) Of the above claim(s) is/are withdrawn from consideration.								
5)□	Claim(s) is/are allowed.								
6)⊠	6)⊠ Claim(s) <u>23-39</u> is/are rejected.								
7) Claim(s) 32-39 is/are objected to.									
8) Claim(s) are subject to restriction and/or election requirement.									
Application Papers									
9) 🔲 -	The specification is objected to by the Examine	er.							
10)☐ The drawing(s) filed on is/are: a)☐ accepted or b)☐ objected to by the Examiner.									
Applicant may not request that any objection to the drawing(s) be held in abeyance. See 37 CFR 1.85(a).									
11)☐ The proposed drawing correction filed on is: a)☐ approved b)☐ disapproved by the Examiner.									
If approved, corrected drawings are required in reply to this Office action.									
12)☐ The oath or declaration is objected to by the Examiner.									
Priority u	inder 35 U.S.C. §§ 119 and 120								
13)	Acknowledgment is made of a claim for foreign	n priority under 3	5 U.S.C. § 119(a	)-(d) or (f).					
a)[	☐ All b)☐ Some * c)☐ None of:								
	1.	s have been rece	eived.						
2. Certified copies of the priority documents have been received in Application No									
<ul> <li>3. Copies of the certified copies of the priority documents have been received in this National Stage application from the International Bureau (PCT Rule 17.2(a)).</li> <li>* See the attached detailed Office action for a list of the certified copies not received.</li> </ul>									
14)∐ A	cknowledgment is made of a claim for domesti	ic priority under 3	5 U.S.C. § 119(€	e) (to a provisional a	pplication).				
a) The translation of the foreign language provisional application has been received.  15) Acknowledgment is made of a claim for domestic priority under 35 U.S.C. §§ 120 and/or 121.									
Attachment	(s)								
2) Notice 3) Inform	e of References Cited (PTO-892) e of Draftsperson's Patent Drawing Review (PTO-948) nation Disclosure Statement(s) (PTO-1449) Paper No(s) 8	4)	Notice of Informal F	(PTO-413) Paper No(s). Patent Application (PTO-1					
J.S. Patent and Tri PTO-326 (Rev		ction Summary		Part of Pa	per No. 10				

Art Unit: 2822

#### **DETAILED ACTION**

This office action is in response to the Applicant's amendment filed June 26, 2002.

# Claim Objections

The objection to claim 24 has been withdrawn due to the Applicant's amendment filed.

Newly added claims 32-39 are objected to because of the following informalities:

Applicant failed to change the dependent claim numbers to correspond to the independent claim numbers. Appropriate correction is required.

### Claim Rejections - 35 USC § 103

The following is a quotation of 35 U.S.C. 103(a) which forms the basis for all obviousness rejections set forth in this Office action:

(a) A patent may not be obtained though the invention is not identically disclosed or described as set forth in section 102 of this title, if the differences between the subject matter sought to be patented and the prior art are such that the subject matter as a whole would have been obvious at the time the invention was made to a person having ordinary skill in the art to which said subject matter pertains. Patentability shall not be negatived by the manner in which the invention was made.

Claims 23-24 and 36 are rejected under 35 U.S.C. 103(a) as being unpatentable over Prior Art Figures 1 and 3a-3b in view of Beasom (4,694,313).

Art Unit: 2822

Prior Art Figures 1 and 3a-3b teach a semiconductor layer 9 having a trench 14 therein; a gate dielectric layer 24 lining the trench; a gate conducting layer 12 in a lower potion of the trench; a dielectric layer 20 in an upper portion of the trench and extending outwardly from the semiconductor layer; source regions 26 adjacent the outwardly extending dielectric layer; source/body contact regions 18 laterally spaced from the gate conducting layer; and a source electrode 22 on the source regions and on the dielectric layer. However, Prior Art Figures 1 and 3a-3b fail to teach a source/body contact regions laterally spaced apart from the gate conducting layer and non-interruptibly contacting the source regions. Beasom teaches source/body contact region 20 laterally spaced apart from the gate conducting layer 16 and non-interruptibly contacting the source regions (Figure 2-4, col. 3, lines 32-68). Beasom further teaches an opening in the source regions exposing the source/body contact regions (Figures 2-4). Therefore, it would have been obvious to one having ordinary skill in the art at the time the invention was made to modify the structure of Prior Art Figures 1 and 3a-3b with the laterally spaced apart source/body contact region of Beasom to provide a device with low series resistance.

Claims 25, 27, 32 and 37 are rejected under 35 U.S.C. 103(a) as being unpatentable over Prior Art Figures 1 and 3a-3b and Beasom (4,694,313) as applied to claims 23-24 above, and further in view of Gilbert et al. (5,349,224).

Prior Art Figures 1 and 3a-3b and Beasom (4,694,313) teach all mentioned in the rejection above. Prior Art Figures 1 and 3a-3b further teach a source electrode 22 on

Art Unit: 2822

the source regions 26, on the dielectric layer 20, and on the source/body contact regions 18. However, Prior Art Figures 1 and 3a-3b and Beasom (4,694,313) fail to teach at least one conductive via between the source electrode and the source/body contact region. Gilbert et al. teach at least one conductive via between the source electrode 90 and the source/body contact region 64 (Figure 5F). Gilbert et al. further teach the source electrode on the source region, on the dielectric layer and on the conductive via (Figure 5F). Therefore, it would have been obvious to one having ordinary skill in the art at the time the invention was made to modify the structure of Prior Art Figures 1 and 3a-3b and the laterally spaced apart source/body contact region of Beasom with the conductive via of Gilbert et al. to be readily integrable in a semiconductor integrated circuit.

Claims 26 and 30 are rejected under 35 U.S.C. 103(a) as being unpatentable over Prior Art Figures 1 and 3a-3b and Beasom (4,694,313) as applied to claims 23-24 above, and further in view of Grabowski et al. (6,140,678).

Prior Art Figures 1 and 3a-3b and Beasom teach all mentioned in the rejections above. However, Prior Art Figures 1 and 3a-3b and Beasom fail to teach a recess over the source/body contact regions wherein the source/body contact regions are recessed within the semiconductor layer adjacent the source regions. Grabowski et al. teach a recess over the source/body contact regions 33 wherein the source/body contact regions are recessed within the semiconductor layer 14 adjacent the source regions 34 (Figure 4A). Therefore, it would have been obvious to one having ordinary skill in the

Art Unit: 2822

art at the time the invention was made to modify the structure of Prior Art Figures 1 and 3a-3b and the laterally spaced apart source/body contact region of Beasom with the recessed areas of Grabowski et al. to reduce hot carrier injection.

Claim 29, 31, and 39 are rejected under 35 U.S.C. 103(a) as being unpatentable over Prior Art Figures 1 and 3a-3b and Beasom (4,694,313) as applied to claim 23-24 above, and further in view of Shih et al. (5,283,452).

Prior Art Figures 1 and 3a-3b and Beasom teach all mentioned in the rejections above. However, Prior Art Figures 1 and 3a-3b and Beasom fail to teach a gate recess depth within a range of 0.2 to 0.8 microns. Shih et al. teach a gate recess depth of 0.25 microns (col. 5, lines 67-68). In regard to claim 31, since Shih et al. teach an optimal gate recess depth of 0.25 microns, it is within the art of ordinary skill to provide an upper surface of the recess of less than 1 micron. Therefore, it would have been obvious to one having ordinary skill in the art at the time the invention was made to modify the structure of Prior Art Figures 1 and 3a-3b and the laterally spaced apart source/body contact region of Beasom with the gate recess depth of Shih et al. to achieve high power operation.

Claims 28 and 38 are rejected under 35 U.S.C. 103(a) as being unpatentable over Prior Art Figures 1 and 3a-3b and Beasom (4,694,313) as applied to claim 23-24 above, and further in view of Singh et al. (5,960,311).

Art Unit: 2822

Prior Art Figures 1 and 3a-3b and Beasom teach all mentioned in the rejections above. However, Prior Art Figures 1 and 3a-3b and Beasom fail to teach a dielectric layer extending from a region equal to or less than about 1 micron. Singh et al. teach a dielectric layer extending from a region from 0.5 to 1.2 microns (col. 5, lines 21-26). Therefore, it would have been obvious to one having ordinary skill in the art at the time the invention was made to modify the structure of Prior Art Figures 1 and 3a-3b and the laterally spaced apart source/body contact region of Beasom with the dielectric layer extending from a region of Singh et al. to reduce the geometries of integrated circuits.

Claim 33 is rejected under 35 U.S.C. 103(a) as being unpatentable over Prior Art Figures 1 and 3a-3b, Beasom (4,694,313) and Gilbert et al. (5,349,224) as applied to claims 23-24 and 32 above, and further in view of Grabowski et al. (6,140,678).

Prior Art Figures 1 and 3a-3b, Beasom and Gilbert et al. teach all mentioned in the rejection above. However, Prior Art Figures 1 and 3a-3b, Beasom (4,694,313) and Gilbert et al. fail to teach a recess over the source/body contact regions wherein the source/body contact regions are recessed within the semiconductor layer adjacent the source regions. Grabowski et al. teach a recess over the source/body contact regions 33 wherein the source/body contact regions are recessed within the semiconductor layer 14 adjacent the source regions 34 (Figure 4A). Therefore, it would have been obvious to one having ordinary skill in the art at the time the invention was made to modify the structure of Prior Art Figures 1 and 3a-3b, the laterally spaced apart

Art Unit: 2822

source/body contact region of Beasom and the conductive via of Gilbert et al. with the recessed areas of Grabowski et al. to improve the on-resistance.

Claim 34 is rejected under 35 U.S.C. 103(a) as being unpatentable over Prior Art Figures 1 and 3a-3b, Beasom (4,694,313) and Gilbert et al. (5,349,224) as applied to claim 23-24 and 32 above, and further in view of Singh et al. (5,960,311).

Prior Art Figures 1 and 3a-3b, Beasom and Gilbert et al. teach all mentioned in the rejection above. However, Prior Art Figures 1 and 3a-3b, Beasom (4,694,313) and Gilbert et al. fail to teach a dielectric layer extending from a region equal to or less than about 1 micron. Singh et al. teach a dielectric layer extending from a region from 0.5 to 1.2 microns (col. 5, lines 21-26). Therefore, it would have been obvious to one having ordinary skill in the art at the time the invention was made to modify the structure of Prior Art Figures 1 and 3a-3b, the laterally spaced apart source/body contact region of Beasom and the conductive via of Gilbert et al. with the dielectric layer extending from a region of Singh et al. to increase the speed of the circuit.

Claim 35 is rejected under 35 U.S.C. 103(a) as being unpatentable over Prior Art Figures 1 and 3a-3b, Beasom (4,694,313) and Gilbert et al. (5,349,224) as applied to claim 23-24 and 32 above, and further in view of Shih et al. (5,283,452).

Prior Art Figures 1 and 3a-3b, Beasom and Gilbert et al. teach all mentioned in the rejection above. However, Prior Art Figures 1 and 3a-3b, Beasom (4,694,313) and Gilbert et al. fail to teach a gate recess depth within a range of 0.2 to 0.8 microns. Shih

Art Unit: 2822

et al. teach a gate recess depth of 0.25 microns (col. 5, lines 67-68). In regard to claim 31, since Shih et al. teach an optimal gate recess depth of 0.25 microns, it is within the art of ordinary skill to provide an upper surface of the recess of less than 1 micron. Therefore, it would have been obvious to one having ordinary skill in the art at the time the invention was made to modify the structure of Prior Art Figures 1 and 3a-3b, the laterally spaced apart source/body contact region of Beasom and the conductive via of Gilbert et al. with the gate recess depth of Shih et al. to eliminate undesirable coupling effects.

#### Conclusion

The prior art made of record and not relied upon is considered pertinent to applicant's disclosure.

The following patents are cited to further show the state of the art with respects to source/body contact regions:

Harada (US 2002/0000608 A1)

Kawaji et al. (6,072,215)

Lizotte (US 6,229,194 B1)

Wu et al. (US 2002/0096709 A1).

Applicant's amendment necessitated the new ground(s) of rejection presented in this Office action. Accordingly, **THIS ACTION IS MADE FINAL**. See MPEP § 706.07(a). Applicant is reminded of the extension of time policy as set forth in 37 CFR 1.136(a).

Art Unit: 2822

A shortened statutory period for reply to this final action is set to expire THREE MONTHS from the mailing date of this action. In the event a first reply is filed within TWO MONTHS of the mailing date of this final action and the advisory action is not mailed until after the end of the THREE-MONTH shortened statutory period, then the shortened statutory period will expire on the date the advisory action is mailed, and any extension fee pursuant to 37 CFR 1.136(a) will be calculated from the mailing date of the advisory action. In no event, however, will the statutory period for reply expire later than SIX MONTHS from the date of this final action.

# Response to Arguments

Applicant's arguments with respect to claims 23-39 have been considered but are most in view of the new ground(s) of rejection.

Any inquiry concerning this communication or earlier communications from the examiner should be directed to Ida M Soward whose telephone number is 703-305-3308. The examiner can normally be reached on Monday - Friday, 7:30 am to 4:00 pm.

If attempts to reach the examiner by telephone are unsuccessful, the examiner's supervisor, Carl Whitehead, Jr. can be reached on 703-308-4940. The fax phone numbers for the organization where this application or proceeding is assigned are 703-308-7722 for regular communications and 703-308-7722 for After Final communications.

Art Unit: 2822

Any inquiry of a general nature or relating to the status of this application or proceeding should be directed to the receptionist whose telephone number is 703-308-0956.

ims August 28, 2002

> CARL WHITEHEAD, JR. C SUPERVISORY PATENT EXAMINER TECHNOLOGY CENTER 2800